## This Page Is Inserted by IFW Operations and is not a part of the Official Record

## **BEST AVAILABLE IMAGES**

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

## IMAGES ARE BEST AVAILABLE COPY.

As rescanning documents will not correct images, please do not report the images to the Image Problem Mailbox.

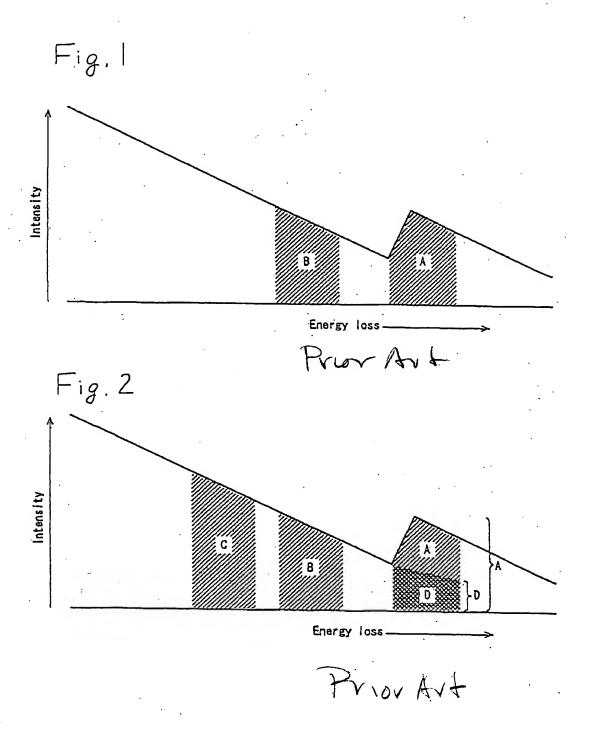
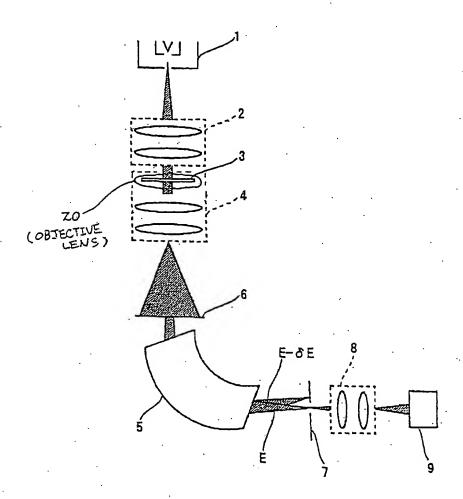
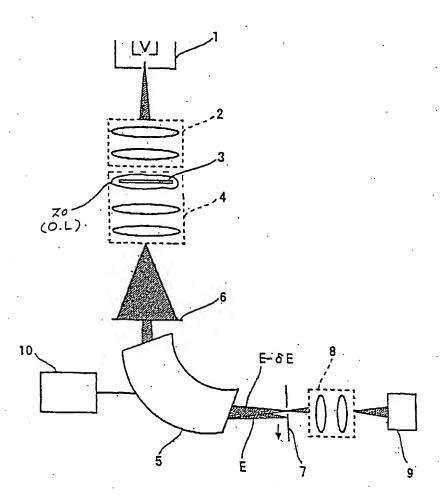


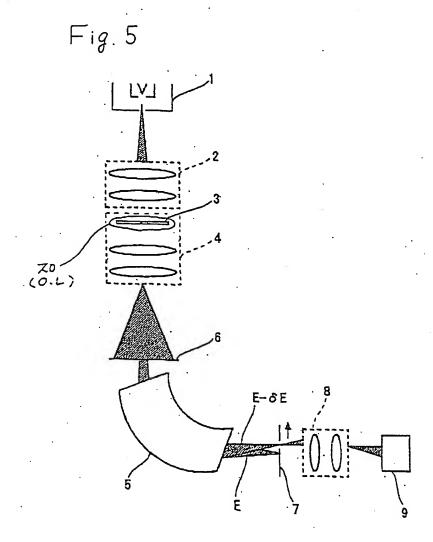
Fig. 3



"Electron Beam Apparatus Having Electron Analyzer and Method of Controlling Lenses"
Inventor: Toshikatsu KANEYAMA
Attorney Docket No. 116-040128

Fig. 4





"Electron Beam Apparatus Having Electron Analyzer and Method of Controlling Lenses"
Inventor: Toshikatsu KANEYAMA
Attorney Docket No. 116-040128

Fig. 6

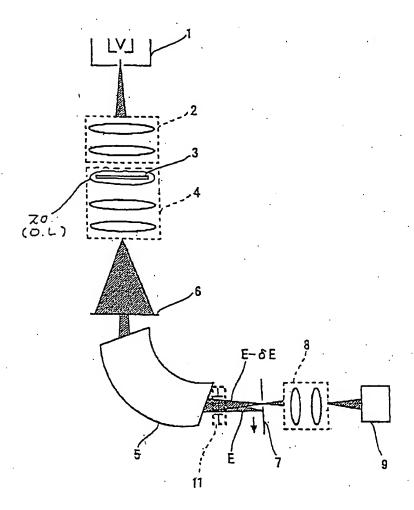


Fig. 7

